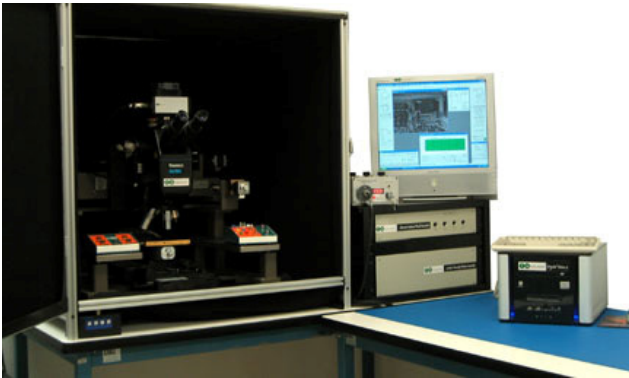


Crystal Vision

InGaAs Camera

Advanced InGaAs technology for enhanced topside & backside photon emission analysis with thermal capabilities



Features & Benefits:

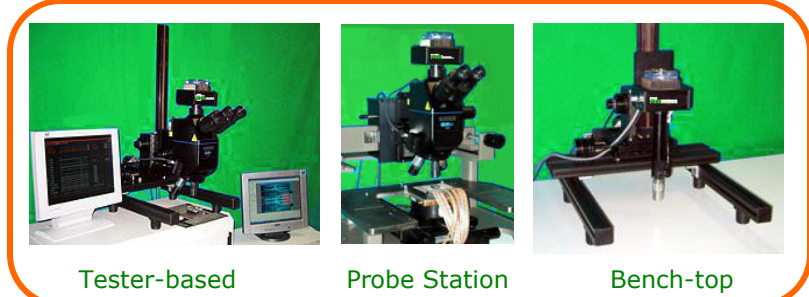
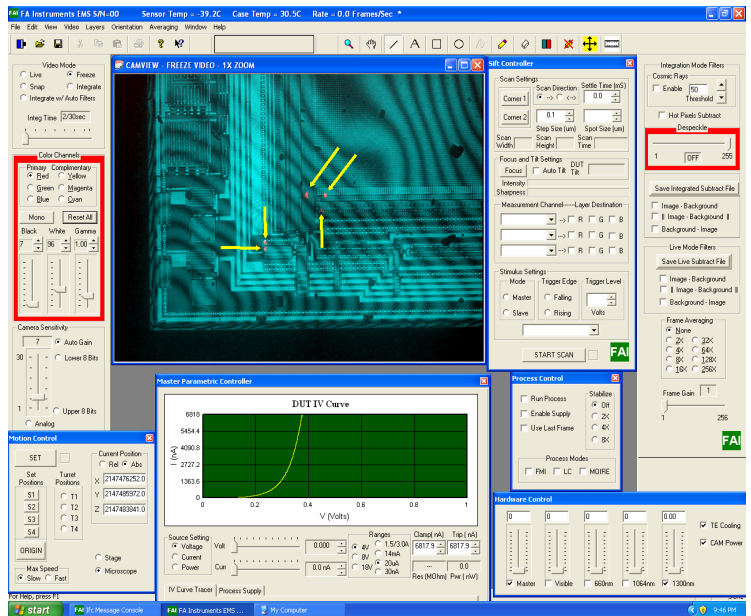
- XP Professional based OS – with advanced imaging functions:
- Automated capture process simplifying emission capture and overlays.
- Filter process for background correction
- Calibration tables matched to the camera – increased sensitivity
- Color overlays and multiple window views for emission comparison
- Histogram and image math functions
- Patent Pending Stabilize Imaging for unsurpassed thermal sensitivity
- Software control of illumination intensity - for multiple laser lines
- Liquid crystal and FMI modules available
- Pixel by Pixel correction
- Navigation control
- Parametric control head option for biasing

InGaAs Camera Specifications

- Detector: Indium Gallium Arsenide (InGaAs)
- Array Format: 320 (H) x 256 (V) Focal Plane Array
- Pixel Size: 30 x 30 microns
- Spectral Response: 900 to 1700 nanometers
- QE: 80-85%
- Optical Fill Factor: >90%
- Thermal Stabilization: Thermoelectric
- Window Material: BK-7 Optical Glass
- Digital Data Real-time, 12-bit, Parallel
- Integration Type: Snapshot Mode or Software Paced Sequential Readout
- Integration Time: Range 1 μ sec to 60 minutes
- Sensitivity: NEI <1x1010 ph/cm2/sec
- Damage Threshold: >1 W/cm2
- Time to Initial Image: 30 sec @ 25°C ambient; \leq 1 sec, not temperature dependent. Full stabilization <5 minutes.
- Cooling Method: Multistage TEC
- Power Dissipation: 12W typical
- Power Connector: Custom controlled via emission software

No LN2 dewars!

Notice: US Export restricted NIR Technology



Tester-based

Probe Station

Bench-top

Versatile mounting options for portable or dark box based systems

